

Features

- N-Channel
60V/4A,
 $R_{DS\ (ON)} = 60m\Omega$ (Typ.) @ $V_{GS}=10V$
- $R_{DS\ (ON)} = 70m\Omega$ (Typ.) @ $V_{GS}=4.5V$
- P-Channel
-60V/-4A,
 $R_{DS\ (ON)} = 50m\Omega$ (Typ.) @ $V_{GS}=-10V$
- $R_{DS\ (ON)} = 65m\Omega$ (Typ.) @ $V_{GS}=-4.5V$
- Super High Dense Cell Design
- Fast Switching

Applications

- Load Switch

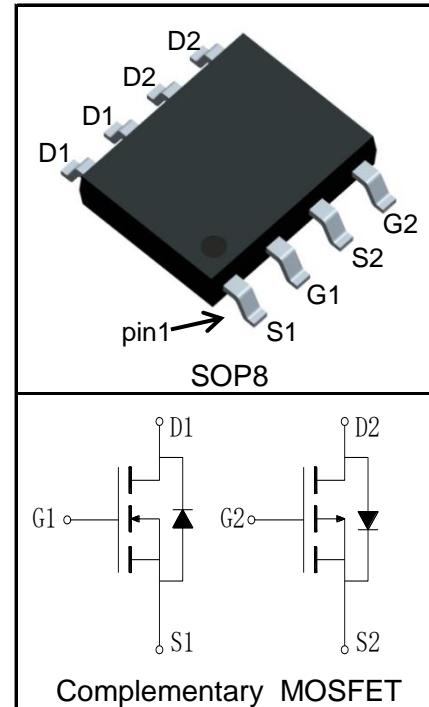


Halogen-Free

Absolute Maximum Ratings

Symbol	Parameter	N-Channel	P-Channel	Unit
Common Ratings ($T_A=25^\circ C$ Unless Otherwise Noted)				
V_{DSS}	Drain-Source Voltage	60	-60	V
V_{GSS}	Gate-Source Voltage	± 20	± 20	
T_J	Maximum Junction Temperature	150	150	$^\circ C$
T_{STG}	Storage Temperature Range	-55 to 150	-55 to 150	$^\circ C$
I_S	Diode Continuous Forward Current	$T_A=25^\circ C$	1.6	-1.6
Mounted on Large Heat Sink				
$I_{DP}^{(1)}$	300 μ s Pulse Drain Current Tested	$T_A=25^\circ C$	16	-16
$I_D^{(2)}$	Continuous Drain Current ($V_{GS}=\pm 10V$)	$T_A=25^\circ C$	4	-4
		$T_A=70^\circ C$	3.2	-3.2
P_D	Maximum Power Dissipation	$T_A=25^\circ C$	2	2
		$T_A=70^\circ C$	1.3	1.3
$R_{\theta JL}$	Thermal Resistance-Junction to Lead	24	24	$^\circ C/W$
$R_{\theta JA}^{(3)}$	Thermal Resistance-Junction to Ambient	62.5	62.5	$^\circ C/W$
Drain-Source Avalanche Ratings				
$E_{AS}^{(4)}$	Avalanche Energy, Single Pulsed	12	20	mJ

Pin Description



Electrical Characteristics ($T_A=25^\circ\text{C}$ Unless Otherwise Noted)

Symbol	Parameter	Test Condition	KS6638HA			Unit	
			Min.	Typ.	Max.		
Static Characteristics							
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}, I_{\text{DS}}=250\mu\text{A}$	N	60		V	
		$V_{\text{GS}}=0\text{V}, I_{\text{DS}}=-250\mu\text{A}$	P	-60			
I_{DSS}	Zero Gate Voltage Drain Current	$V_{\text{DS}}=60\text{V}, V_{\text{GS}}=0\text{V}$	N		1	μA	
		$T_J=125^\circ\text{C}$			30		
		$V_{\text{DS}}=-60\text{V}, V_{\text{GS}}=0\text{V}$	P		-1		
		$T_J=125^\circ\text{C}$			-30		
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{DS}}=250\mu\text{A}$	N	1.1	1.6	V	
		$V_{\text{DS}}=V_{\text{GS}}, I_{\text{DS}}=-250\mu\text{A}$	P	-1.1	-1.6		
I_{GSS}	Gate Leakage Current	$V_{\text{GS}}=\pm 20\text{V}, V_{\text{DS}}=0\text{V}$	N		± 100	nA	
		$V_{\text{GS}}=\pm 20\text{V}, V_{\text{DS}}=0\text{V}$	P		± 100		
$R_{\text{DS}(\text{ON})}^{(5)}$	Drain-Source On-state Resistance	$V_{\text{GS}}=10\text{V}, I_{\text{DS}}=4\text{A}$	N		60	$\text{m}\Omega$	
		$V_{\text{GS}}=-10\text{V}, I_{\text{DS}}=-4\text{A}$	P		50		
		$V_{\text{GS}}=4.5\text{V}, I_{\text{DS}}=3\text{A}$	N		70		
		$V_{\text{GS}}=-4.5\text{V}, I_{\text{DS}}=-3\text{A}$	P		65		
Diode Characteristics							
$V_{\text{SD}}^{(5)}$	Diode Forward Voltage	$I_{\text{SD}}=4\text{A}, V_{\text{GS}}=0\text{V}$	N		0.84	V	
		$I_{\text{SD}}=-4\text{A}, V_{\text{GS}}=0\text{V}$	P		-0.84		
t_{rr}	Reverse Recovery Time	N-Channel $I_{\text{SD}}=4\text{A}, dI_{\text{SD}}/dt=100\text{A}/\mu\text{s}$	N		21	ns	
			P		15		
Q_{rr}	Reverse Recovery Charge		N		12	nC	
			P		9		
Dynamic Characteristics ⁽⁶⁾							
R_{G}	Gate Resistance	$V_{\text{GS}}=0\text{V}, V_{\text{DS}}=0\text{V}, F=1\text{MHz}$	N		1.2	Ω	
			P		4.8		
C_{iss}	Input Capacitance	N-Channel $V_{\text{GS}}=0\text{V}, V_{\text{DS}}=30\text{V}$, Frequency=1.0MHz	N		430	pF	
			P		1450		
C_{oss}	Output Capacitance		N		70		
			P		110		
C_{rss}	Reverse Transfer Capacitance		N		30		
			P		85		

Electrical Characteristics ($T_A=25^\circ\text{C}$ Unless Otherwise Noted)

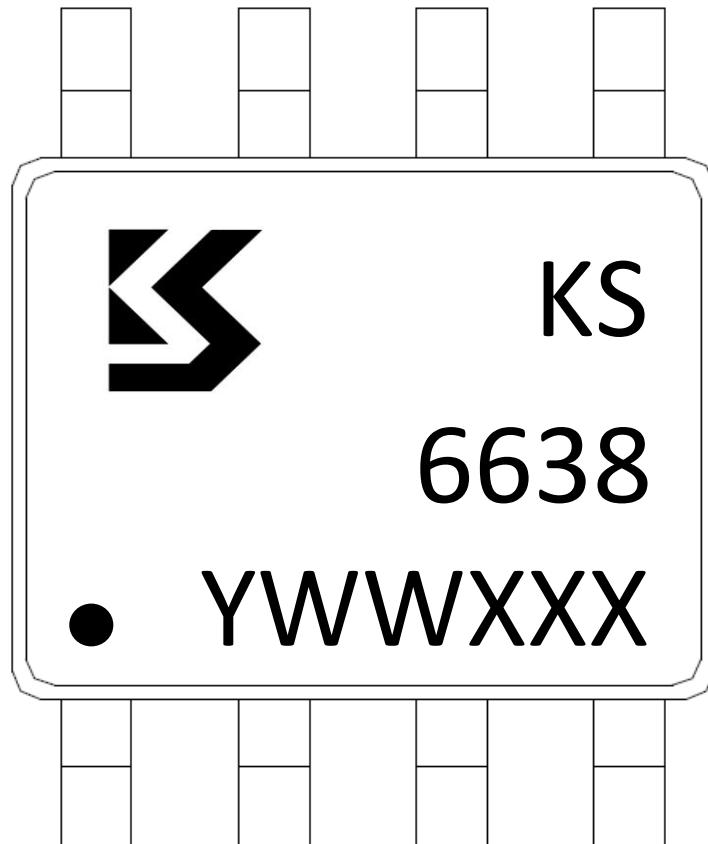
Symbol	Parameter	Test Condition	KS6638HA			Unit
			Min.	Typ.	Max.	
Dynamic Characteristics^⑥						
$t_{d(\text{ON})}$	Turn-on Delay Time	N-Channel $V_{DD}=30V$, $I_{DS}=4A$, $V_{GEN}=10V$, $R_G=3\Omega$	N	7		ns
			P	8		
			N	14		
			P	15		
	Turn-off Delay Time	P-Channel $V_{DD}=-30V$, $I_{DS}=-4A$, $V_{GEN}=-10V$, $R_G=3\Omega$	N	27		
			P	39		
			N	11		
			P	26		
Gate Charge Characteristics^⑥						
Q_g	Total Gate Charge	N-Channel $V_{DS}=30V$, $V_{GS}=10V$, $I_{DS}=4A$	N	14		nC
			P	20		
	Gate-Source Charge	P-Channel $V_{DS}=-30V$, $V_{GS}=-10V$, $I_{DS}=-4A$	N	3.1		
			P	4.3		
Q_{gd}	Gate-Drain Charge		N	3.8		
			P	5.5		

Notes:

- ①Pulse width limited by safe operating area.
- ②Calculated continuous current based on maximum allowable junction temperature.
- ③When mounted on 1 inch square copper board, $t \leq 10\text{sec}$. The value in any given application depends on the user's specific board design.
- ④Limited by $T_{J\max}$. Starting $T_J = 25^\circ\text{C}$, N Channel: $L = 0.5\text{mH}$, $R_G = 25\Omega$, $I_{AS} = 7\text{A}$, $V_{GS} = 10\text{V}$, P-Channel: $L = 0.5\text{mH}$, $R_G = 25\Omega$, $I_{AS} = -9\text{A}$, $V_{GS} = -10\text{V}$, Part not recommended for use above this value.
- ⑤Pulse test; Pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$.
- ⑥Guaranteed by design, not subject to production testing.

Ordering and Marking Information

Device	Package	Packaging	Quantity	Reel Size	Tape width
KS6638HA	SOP8	Tape&Reel	3000	13"	12mm

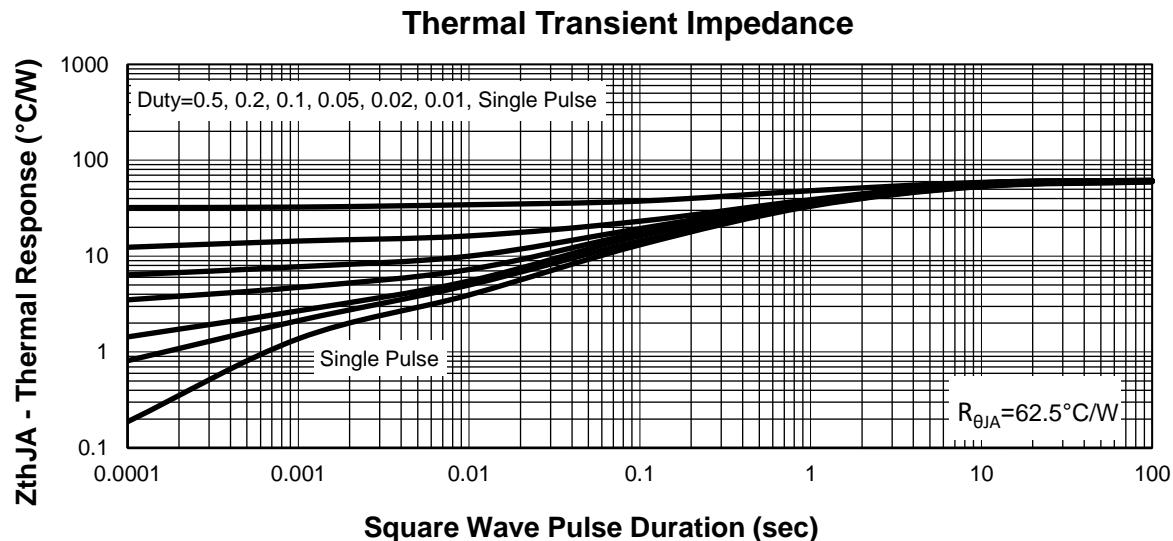
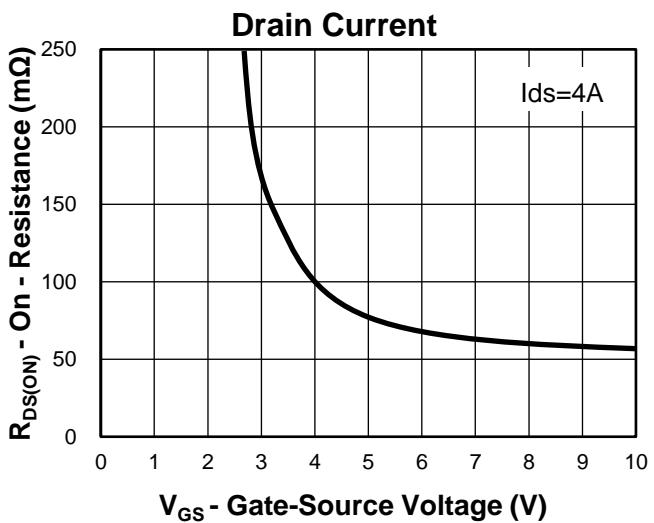
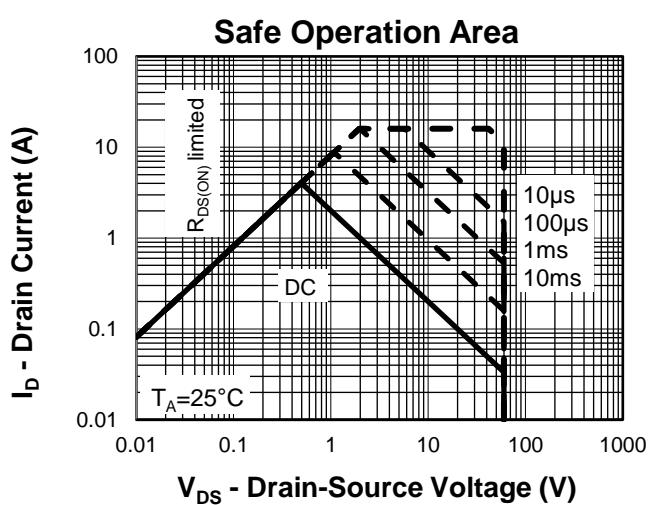
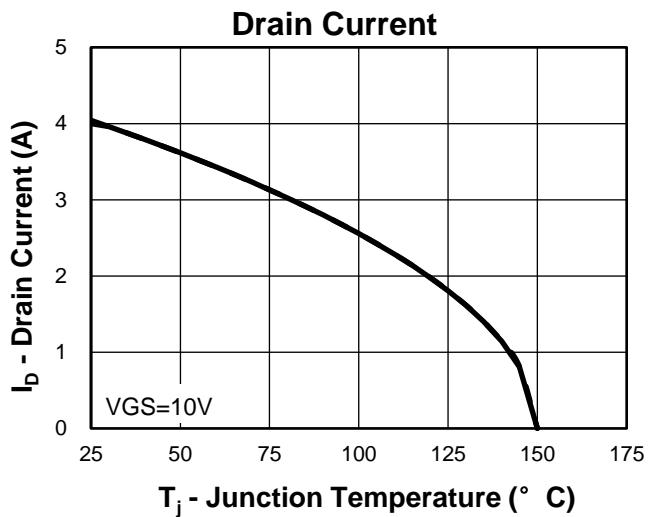
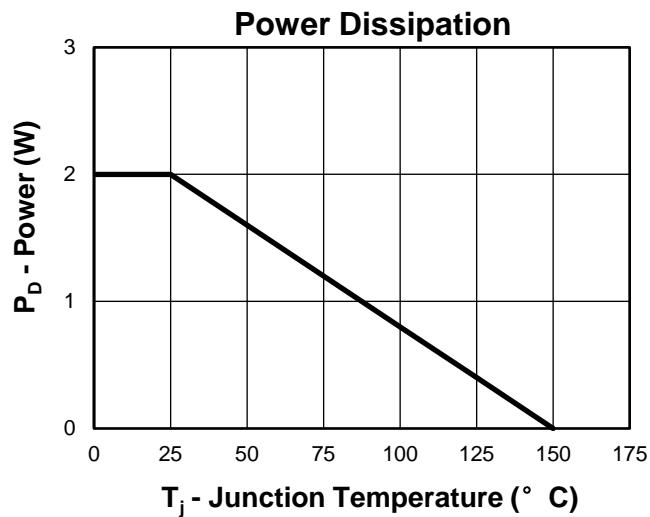


Y =Year,2017-A,2018-B,etc.

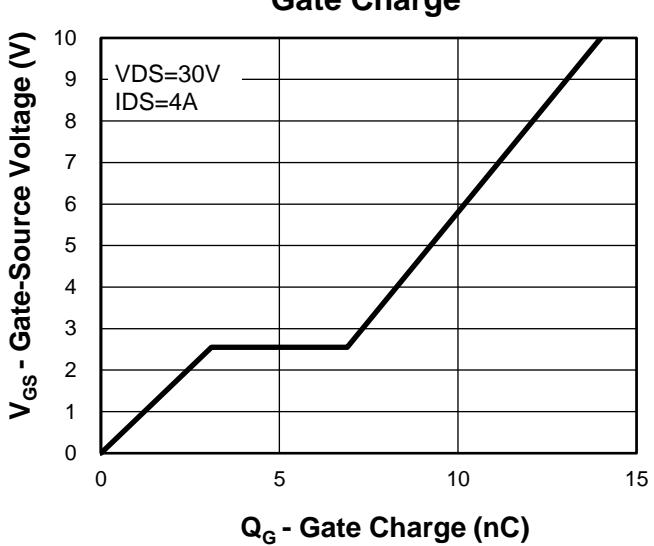
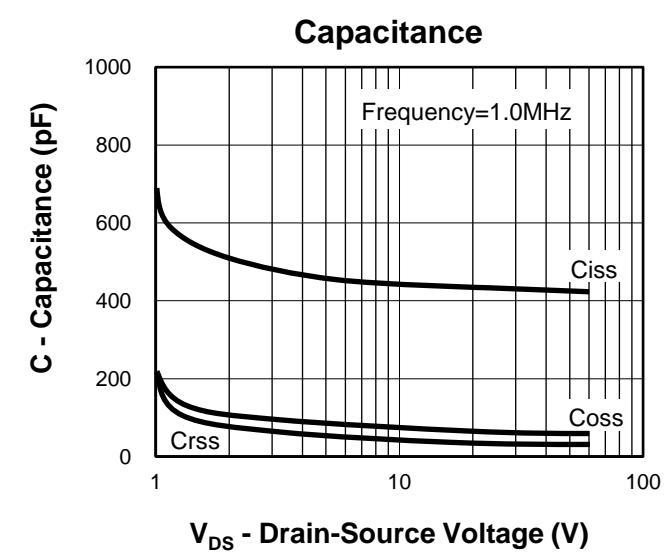
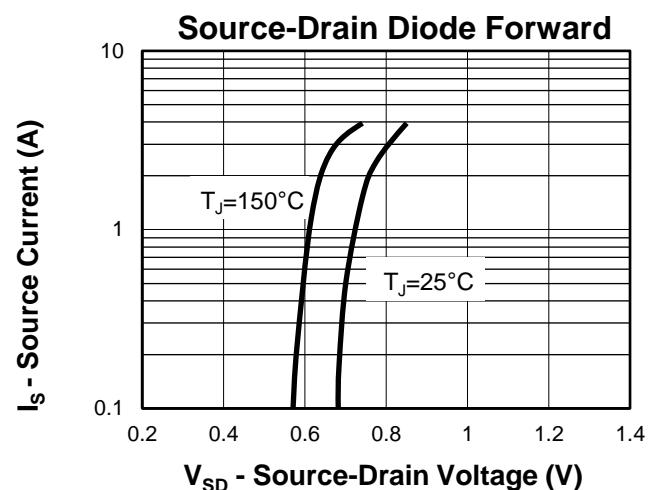
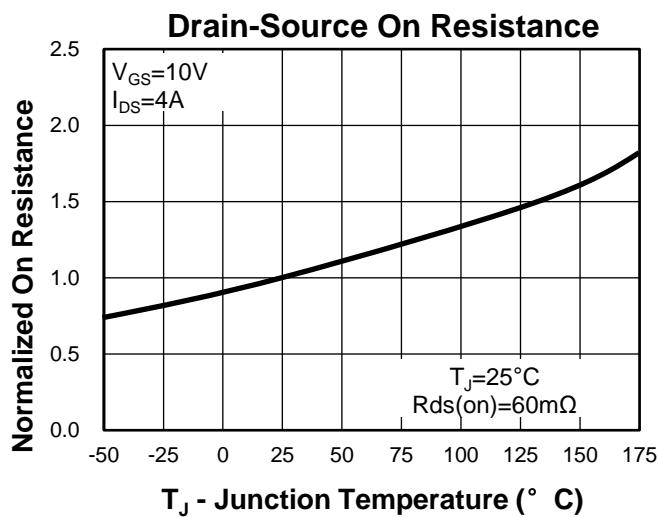
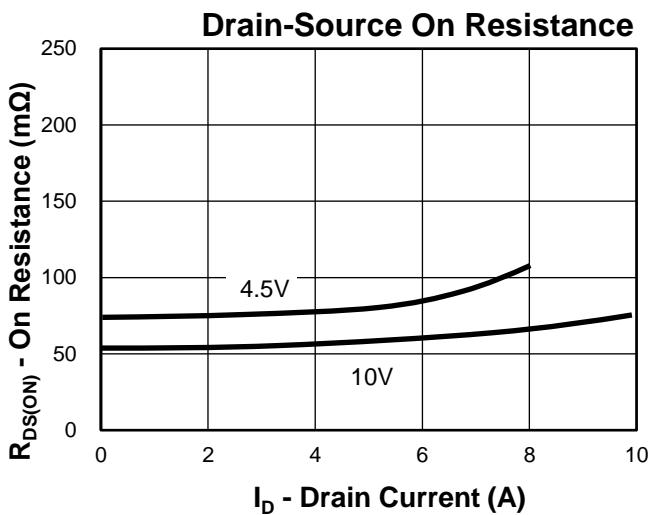
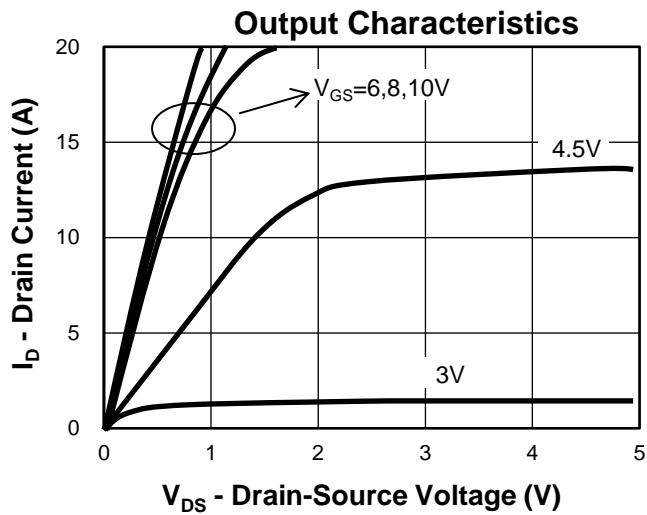
WW =Week.

XXX =Lot number.

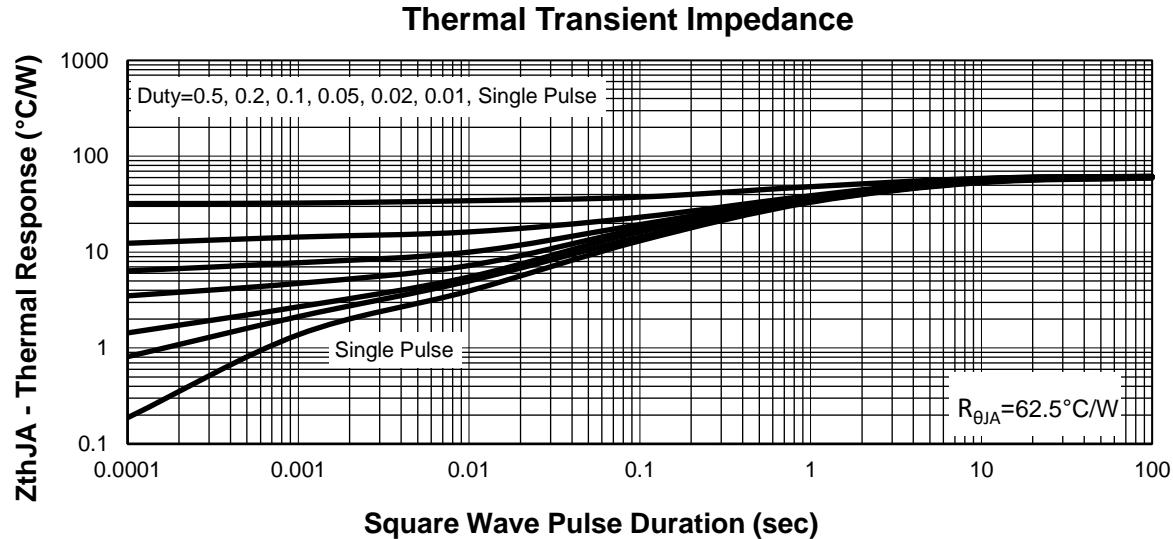
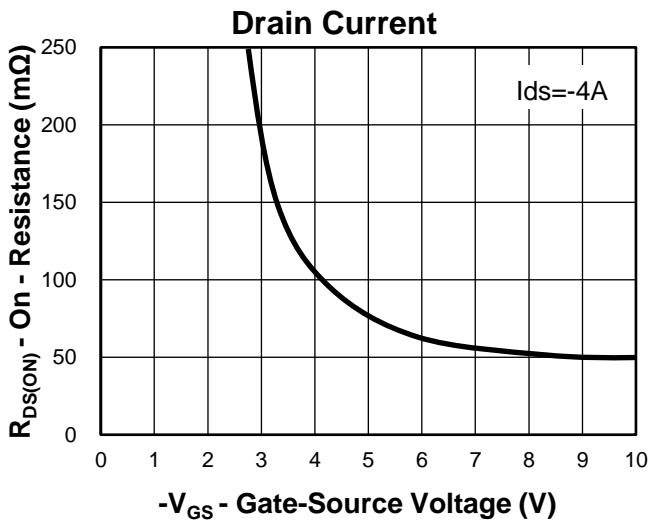
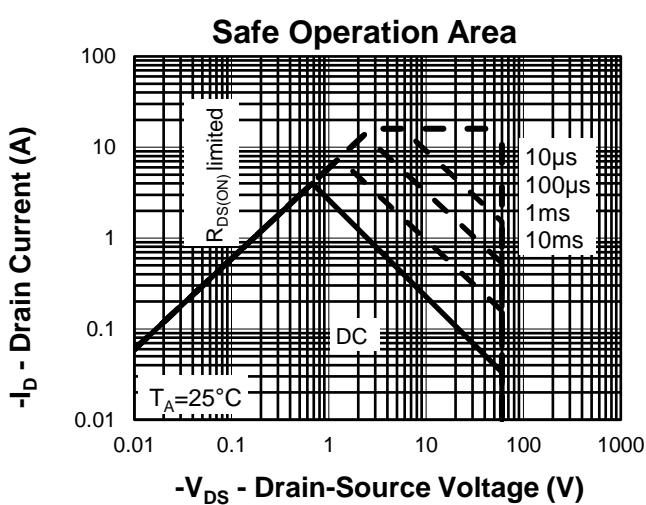
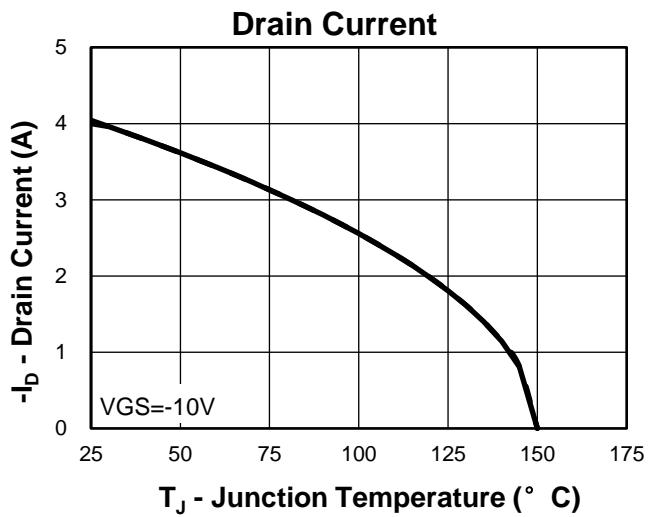
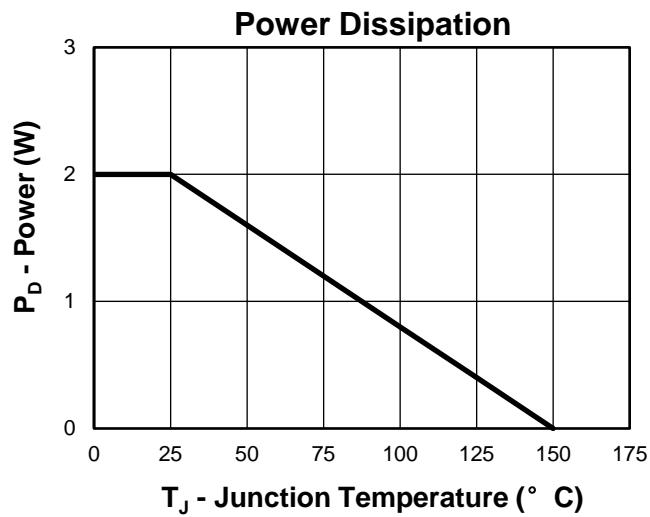
Typical Characteristics(N-Channel)



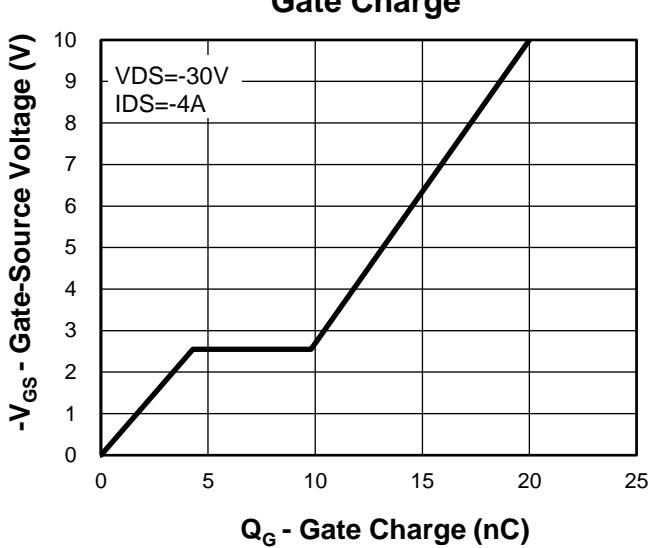
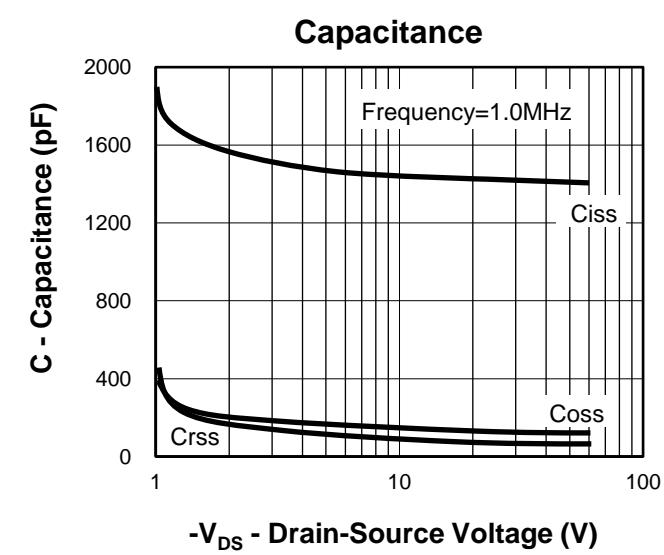
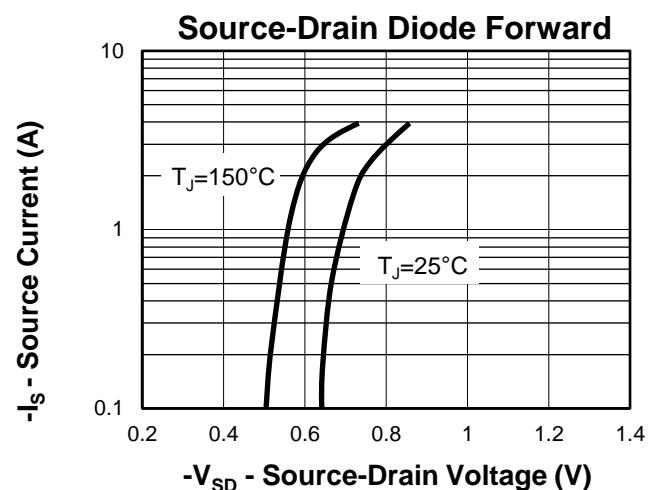
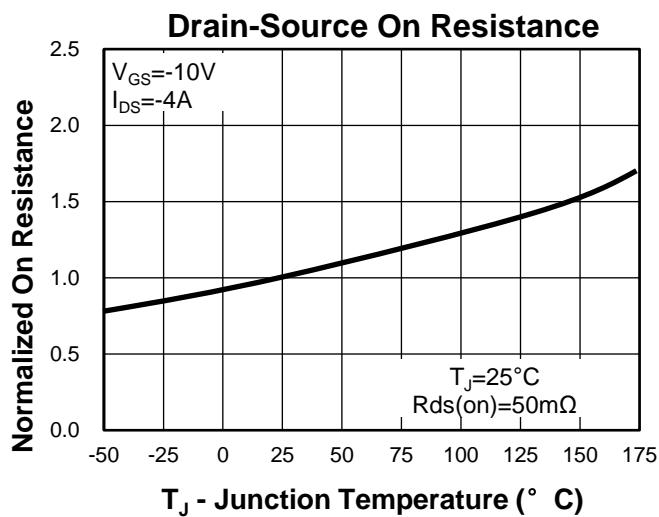
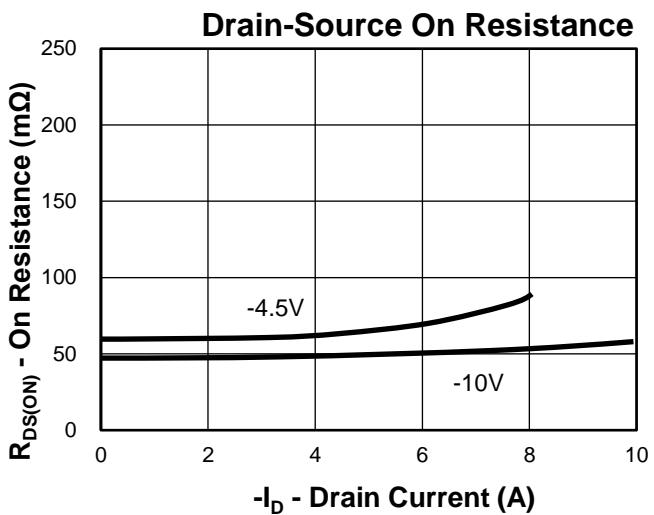
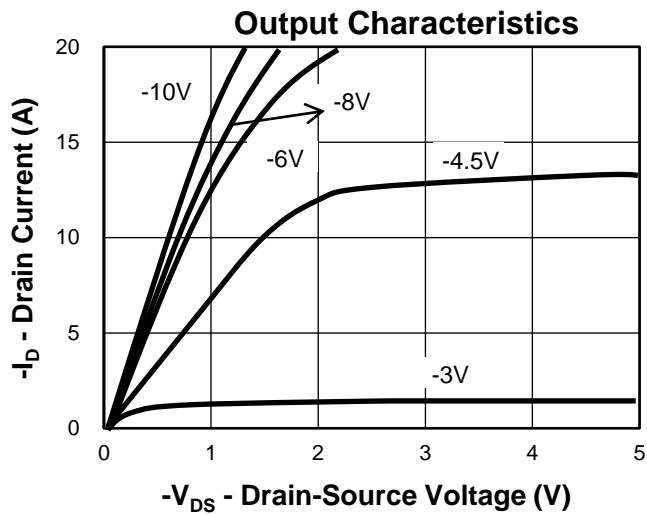
Typical Characteristics(N-Channel)

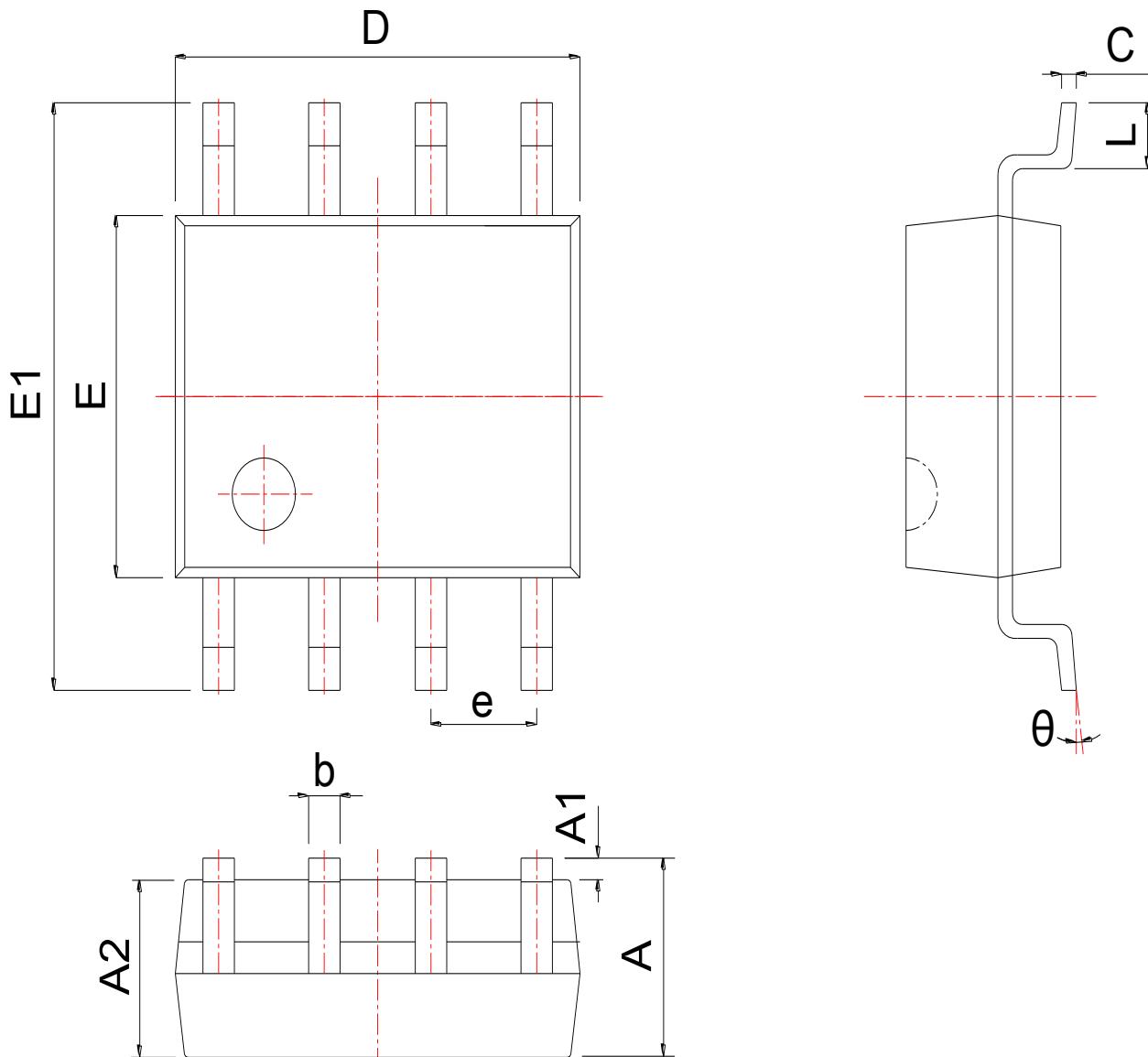


Typical Characteristics(P-Channel)



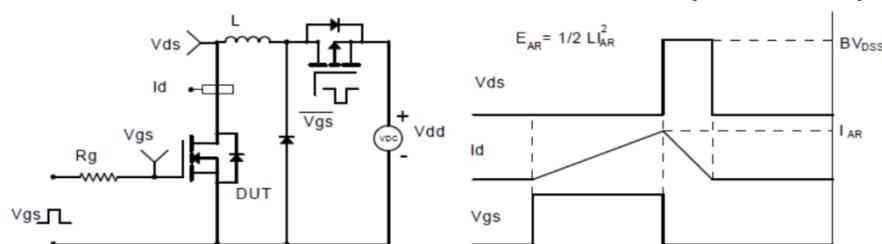
Typical Characteristics(P-Channel)



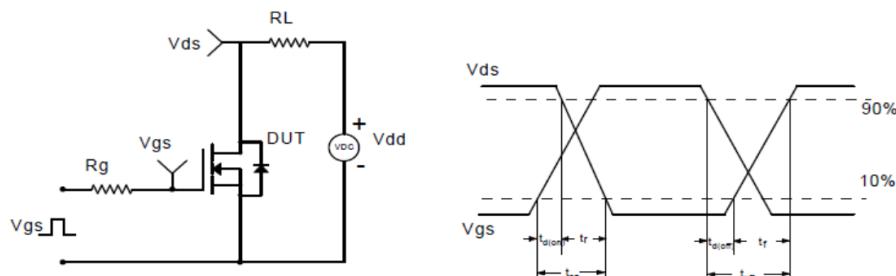
Package Information
SOP8


SYMBOL	MM			INCH		
	MIN	NOM	MAX	MIN	NOM	MAX
A	1.300	1.525	1.750	0.051	0.060	0.069
A1	0.050	0.150	0.250	0.002	0.006	0.010
A2	1.350	1.450	1.550	0.053	0.057	0.061
b	0.330	0.420	0.510	0.013	0.017	0.020
c	0.170	0.210	0.250	0.007	0.008	0.010
D	4.700	4.900	5.100	0.185	0.193	0.201
E	3.800	3.900	4.000	0.150	0.154	0.157
E1	5.800	6.000	6.200	0.228	0.236	0.244
e	1.270 BSC			0.050 BSC		
L	0.400	0.835	1.270	0.016	0.033	0.050
θ	0°		8°	0°		8°

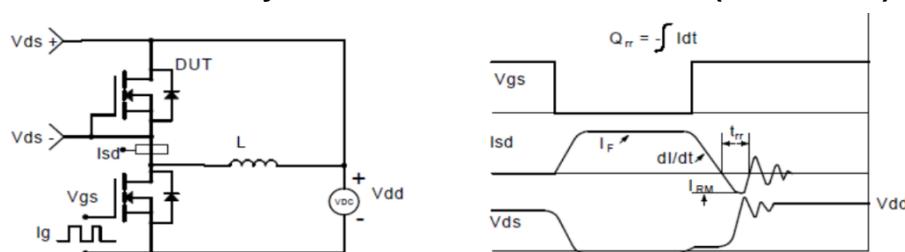
Avalanche Test Circuit and Waveforms(N-Channel)



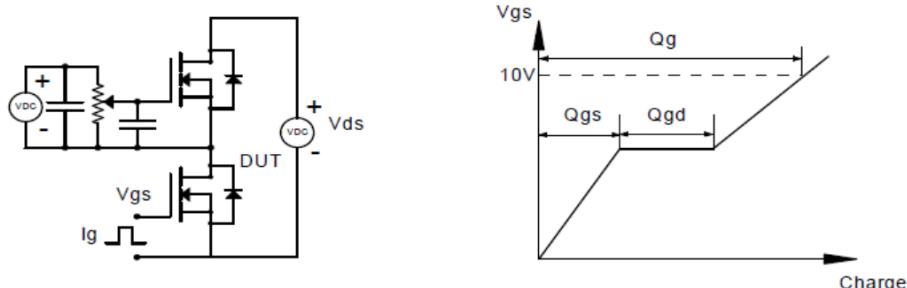
Switching Time Test Circuit and Waveforms(N-Channel)



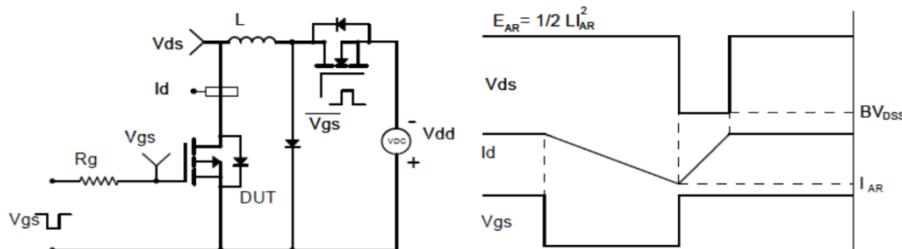
Diode Recovery Test Circuit and Waveforms(N-Channel)



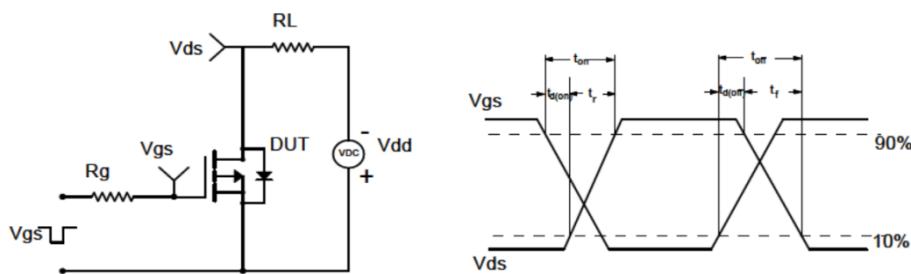
Gate Charge Test Circuit and Waveform(N-Channel)



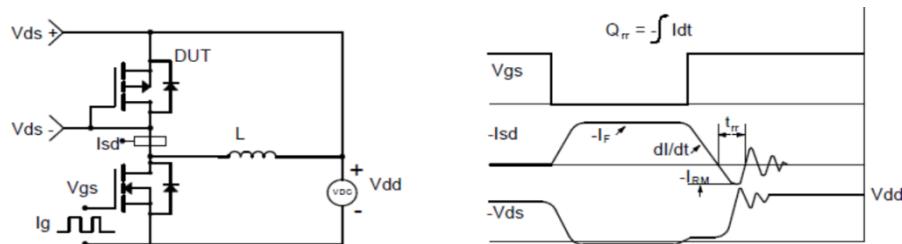
Avalanche Test Circuit and Waveforms(P-Channel)



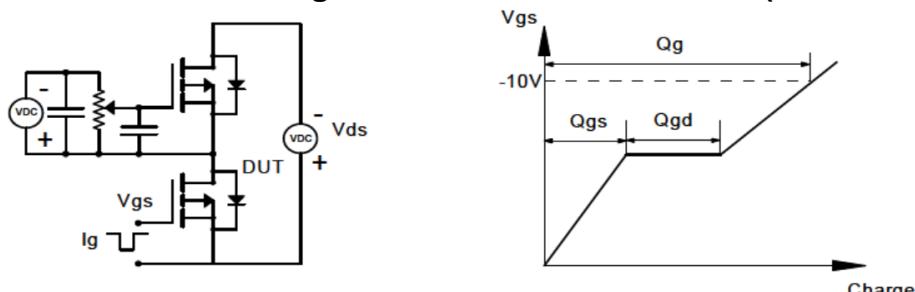
Switching Time Test Circuit and Waveforms(P-Channel)



Diode Recovery Test Circuit and Waveforms(P-Channel)



Gate Charge Test Circuit and Waveform(P-Channel)



Customer Service

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